



3D LEADED DEVICE PATENTS AWARDED

Monday July 3, 2000, 1:00 pm Eastern Time

Elwin M. Beaty, President of Scanner Technologies Corporation, announced today the award of two patents for its stereo vision inspection equipment. Patent numbers 5,909,285 and 6,055,054 relate to the three-dimensional inspection of leaded integrated circuits. Mr. Beaty stated that the UltraVim product line incorporating this technology has been responsible for achieving increased market share in the device measurement segment of the electronics industry. Scanner Technologies is the world leader in the development of stereo vision based 3D inspection technology.